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Complete set of claims

- 1.(Currently amended) A negative photoresist composition comprising:
- a) an alkali soluble polymer consisting occupation of unit of structure 1,

$$(CH_2)_n$$
 Rf_1
 Rf_2

where Rf₁ and Rf₂ are independently a perfluorinated or partially fluorinated alkyl group; and,

n is 1-8,

- b) a single or mixture of photoacid generators; and,
- c) a crosslinking agent.
- 2.(Delete) The photoresist composition according to claim 1, where the polymer contains other units.
- 3.(Delete) The photoresist composition according to claim 2, where the other units are selected from tetrafluoroethylene, ethylene, cycloalkenes, substituted cycloalkenes, maleic anhydride, cyanoacrylate and cyanomethacrylate.
- 4. (Original) The photoresist composition according to claim 1, where the polymer is poly[5-(2-trifluoromethyl-1,1,1-trifluoro-2-hydroxypropyl)-2-norbornene].

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- 5. (Original) The photoresist composition according to claim 1, where in the polymer, n is 1.
- 6. (Original) The photoresist composition according to claim 1, further comprising a base.
- 7. (Original) The photoresist composition according to claim 6, where the base is selected from tetrabutylammonium hydroxide, triethanolamine, diethanol amine, trioctylamine, n-octylamine, trimethylsulfonium hydroxide, triphenylsulfonium hydroxide, bis(t-butylphenyl)iodonium cyclamate and tris(tert-butylphenyl)sulfonium cyclamate.
- 8. (Original) A process for imaging a negative photoresist comprising the steps of:
- a) forming on a substrate a photoresist coating from the photoresist composition of claim 1;
- b) image-wise exposing the photoresist coating;
- postexposure baking the photoresist coating; and
- d) developing the photoresist coating with an aqueous alkaline solution.
- 9. (Original) The process of claim 8, where the image-wise exposure wavelength is below 200 nm.
- 10. (Original) The process according to claim 8 where the aqueous alkaline solution comprises tetramethylammonium hydroxide.
- 11.(Original) The process according to claim 8 where the aqueous alkaline solution further comprises a surfactant.